



US00D650405S

(12) **United States Design Patent**
Nusser

(10) **Patent No.:** **US D650,405 S**

(45) **Date of Patent:** **** Dec. 13, 2011**

(54) **MICROSCOPE ASSEMBLY**

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(**) Term: **14 Years**

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(30) **Foreign Application Priority Data**

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(51) **LOC (9) Cl.** **16-06**

(52) **U.S. Cl.** **D16/131**

(58) **Field of Classification Search** D16/130,
D16/131; 359/368, 374, 382, 384, 375, 376,
359/377, 379, 380, 381, 383, 385; 248/123.2,
248/280.11; 351/212, 221; 606/1; 600/427;
D21/483

See application file for complete search history.

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(57) **CLAIM**

The ornamental design for a microscope assembly, as shown and described.

DESCRIPTION

FIG. 1 is a perspective view of the microscope assembly of my new design;

FIG. 2 is a rear elevation view of said microscope assembly of FIG. 1;

FIG. 3 is a left side elevation view of said microscope assembly of FIG. 1;

FIG. 4 is a bottom plan view of said microscope assembly of FIG. 1;

FIG. 5 is a front elevation view of said microscope assembly of FIG. 1;

FIG. 6 is a right side elevation view of said microscope assembly of FIG. 1; and,

FIG. 7 is a top plan view of said microscope assembly of FIG. 1.

FIG. 8 is a perspective view of a second embodiment of the microscope assembly of my new design;

FIG. 9 is a rear elevation view of said microscope assembly of FIG. 8;

FIG. 10 is a left side elevation view of said microscope assembly of FIG. 8;

FIG. 11 is a bottom plan view of said microscope assembly of FIG. 8;

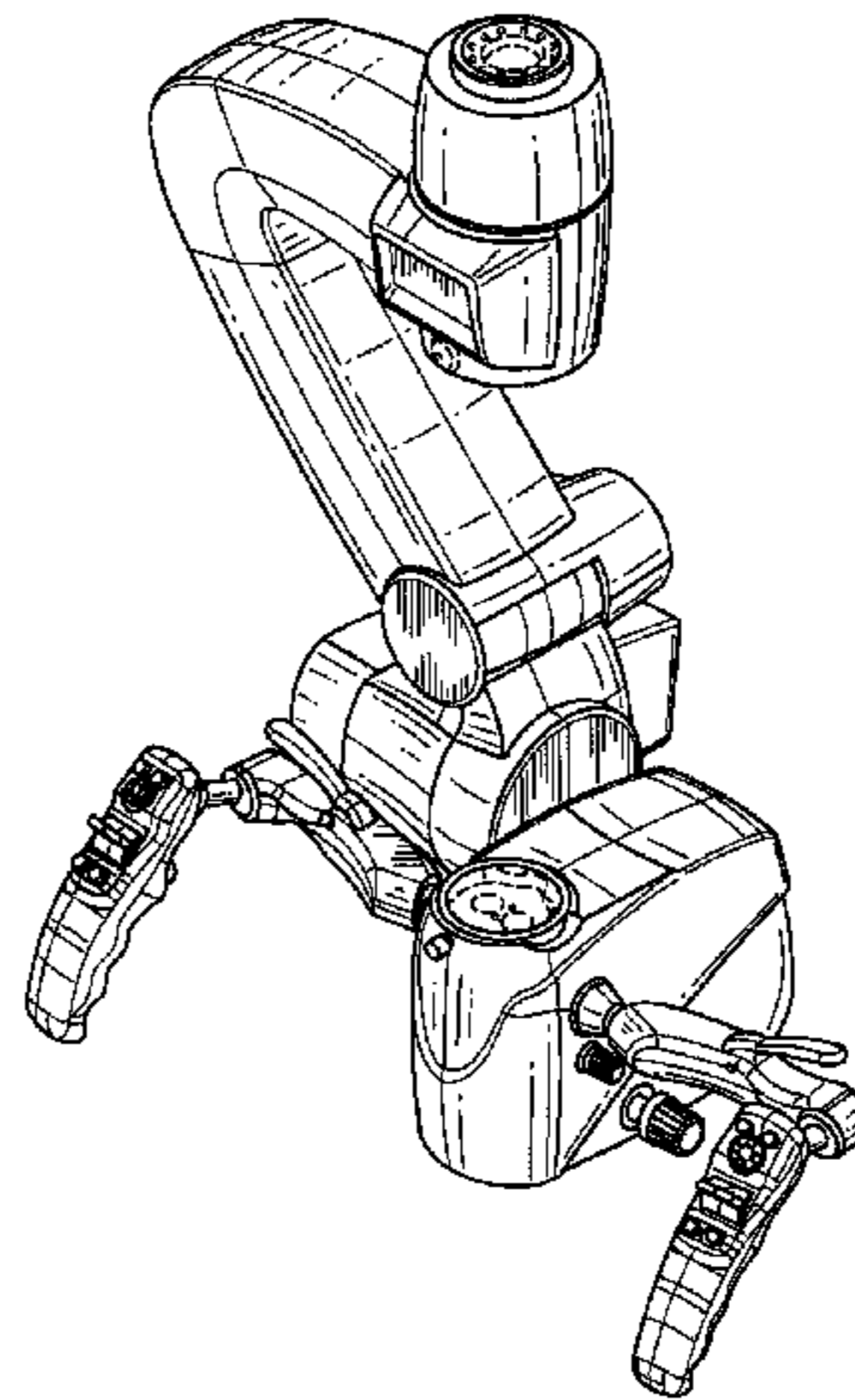
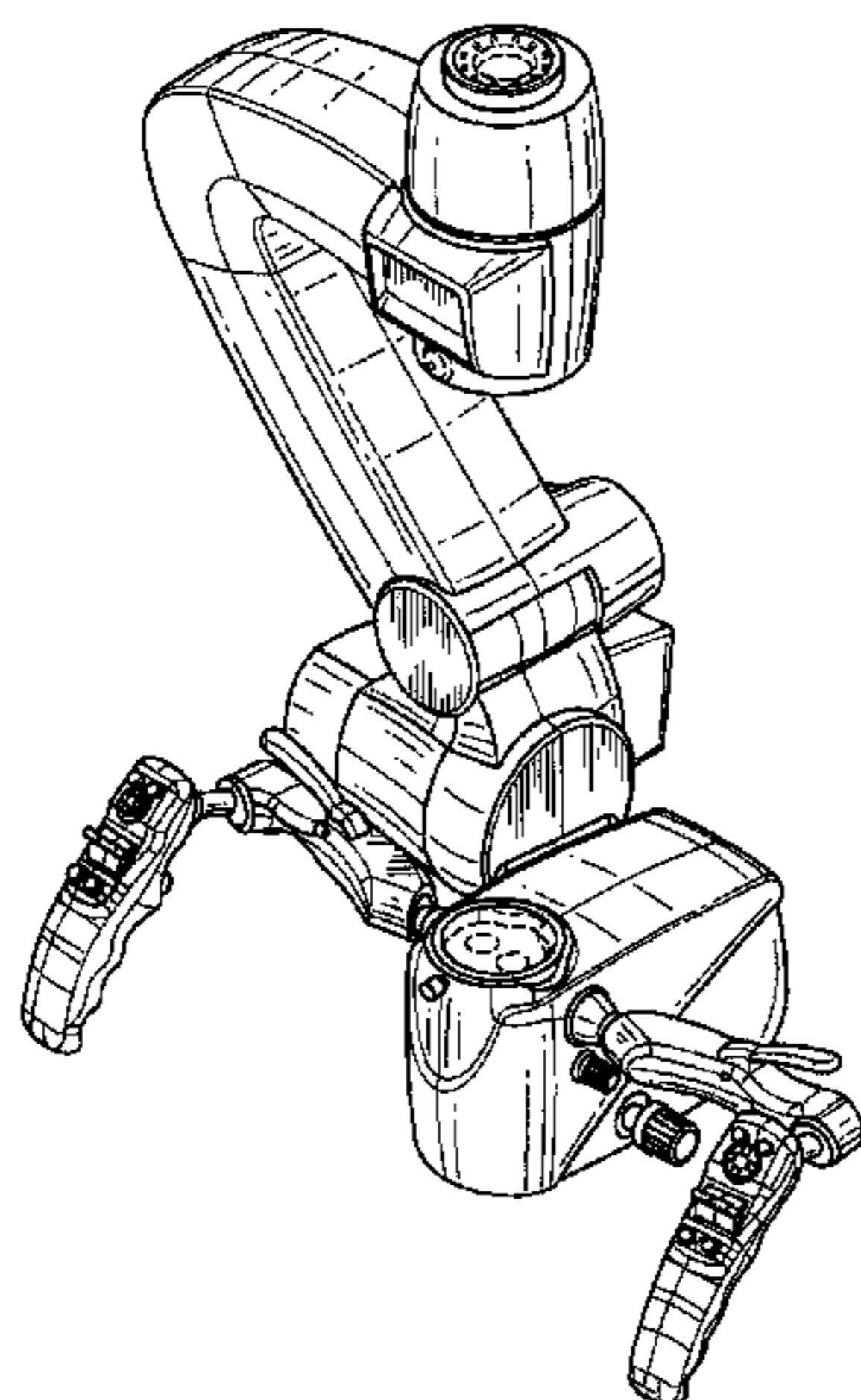
FIG. 12 is a front elevation view of said microscope assembly of FIG. 8;

FIG. 13 is a right side elevation view of said microscope assembly of FIG. 8; and,

FIG. 14 is a top plan view of said microscope assembly of FIG. 8.

The broken lines from no part of the claimed design.

1 Claim, 14 Drawing Sheets



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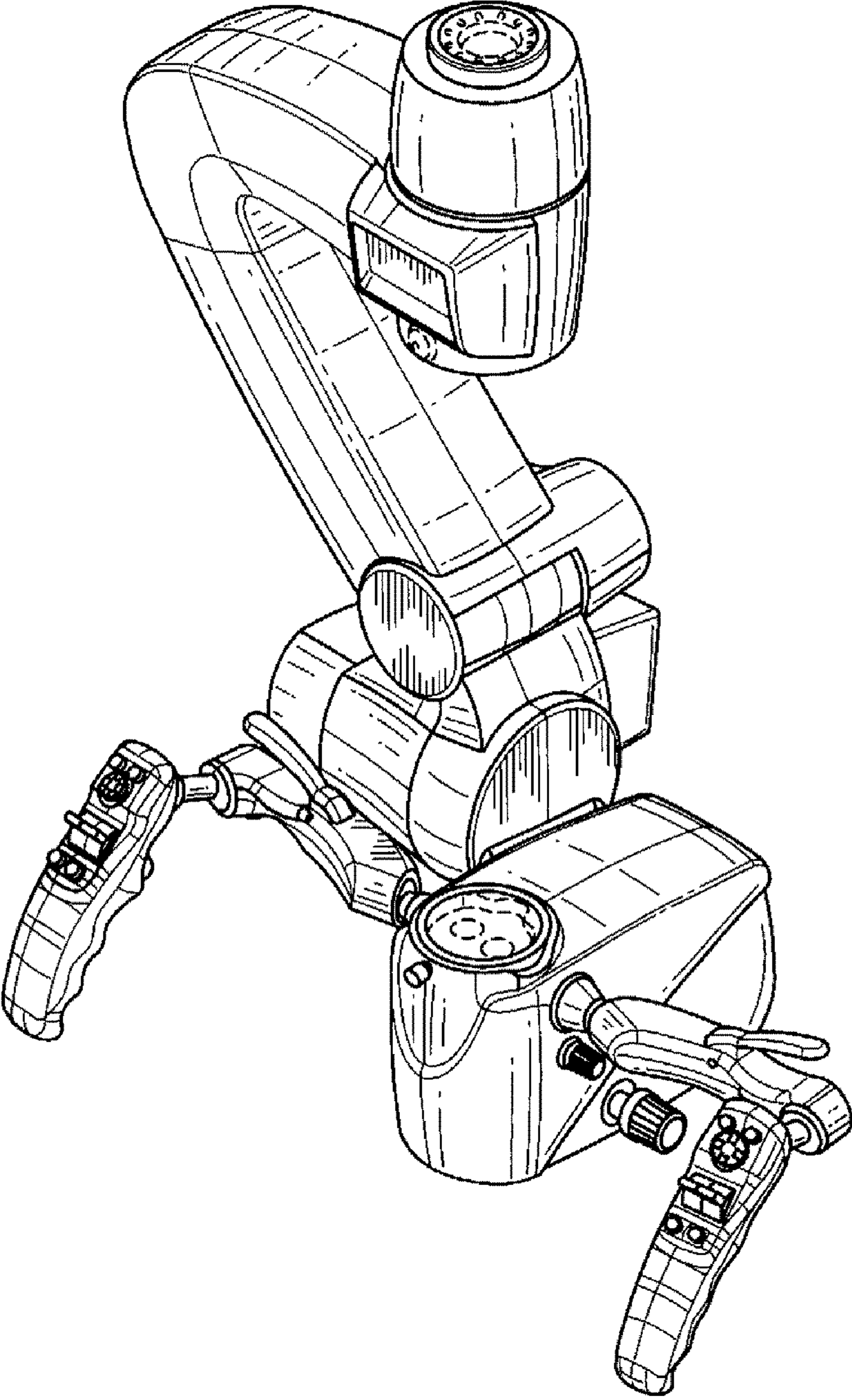


FIG. 1

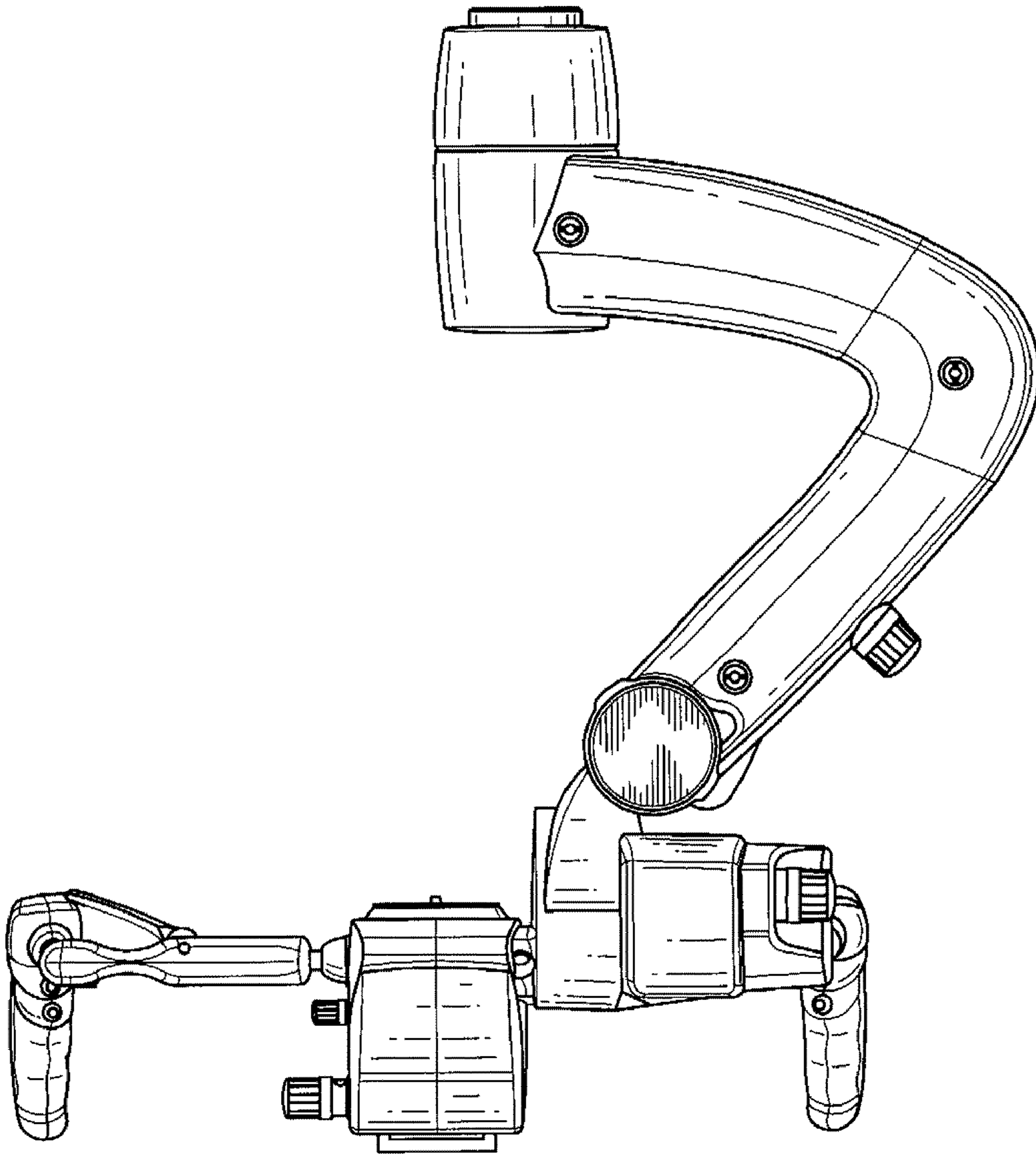


FIG. 2

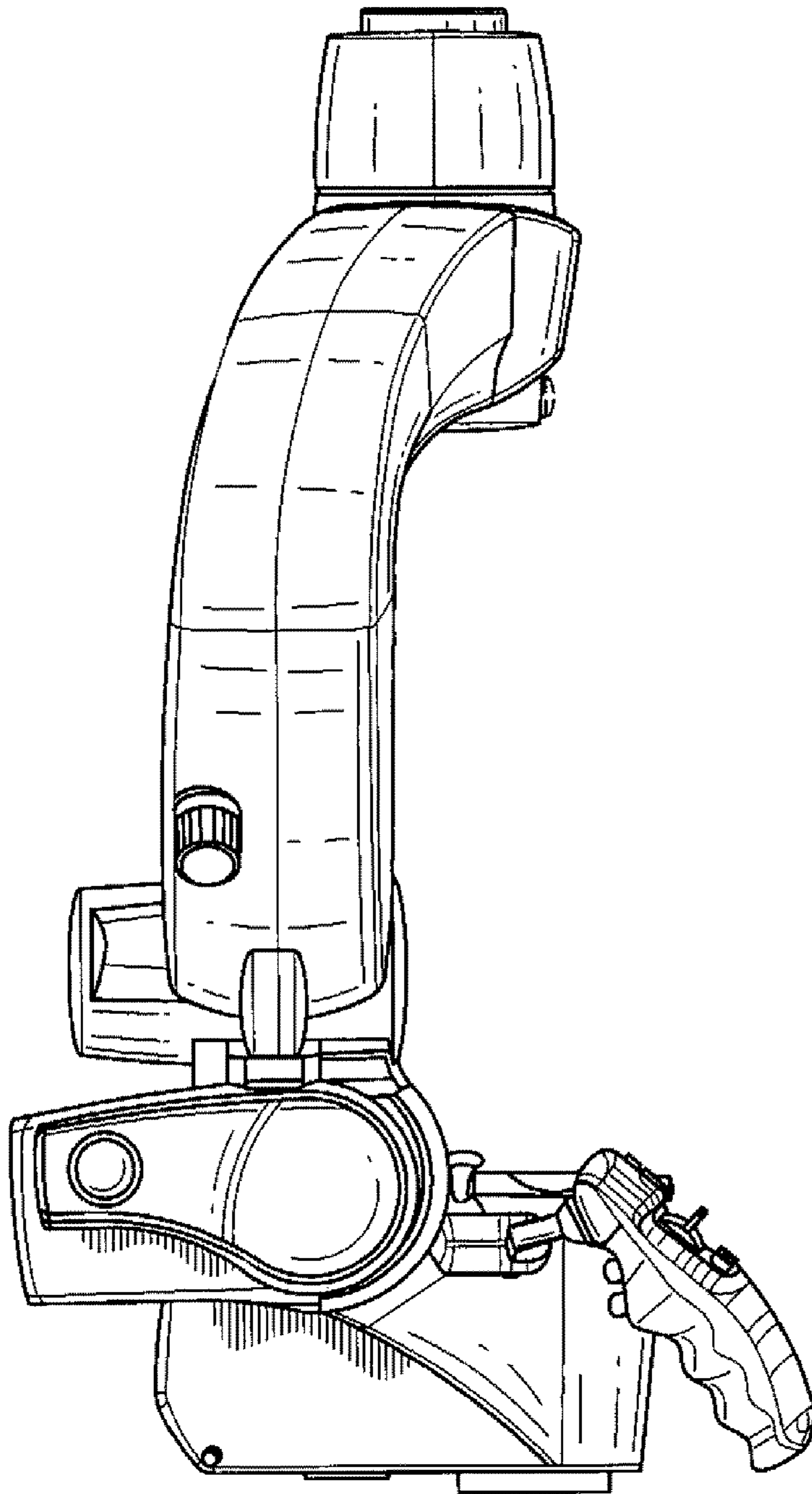


FIG. 3

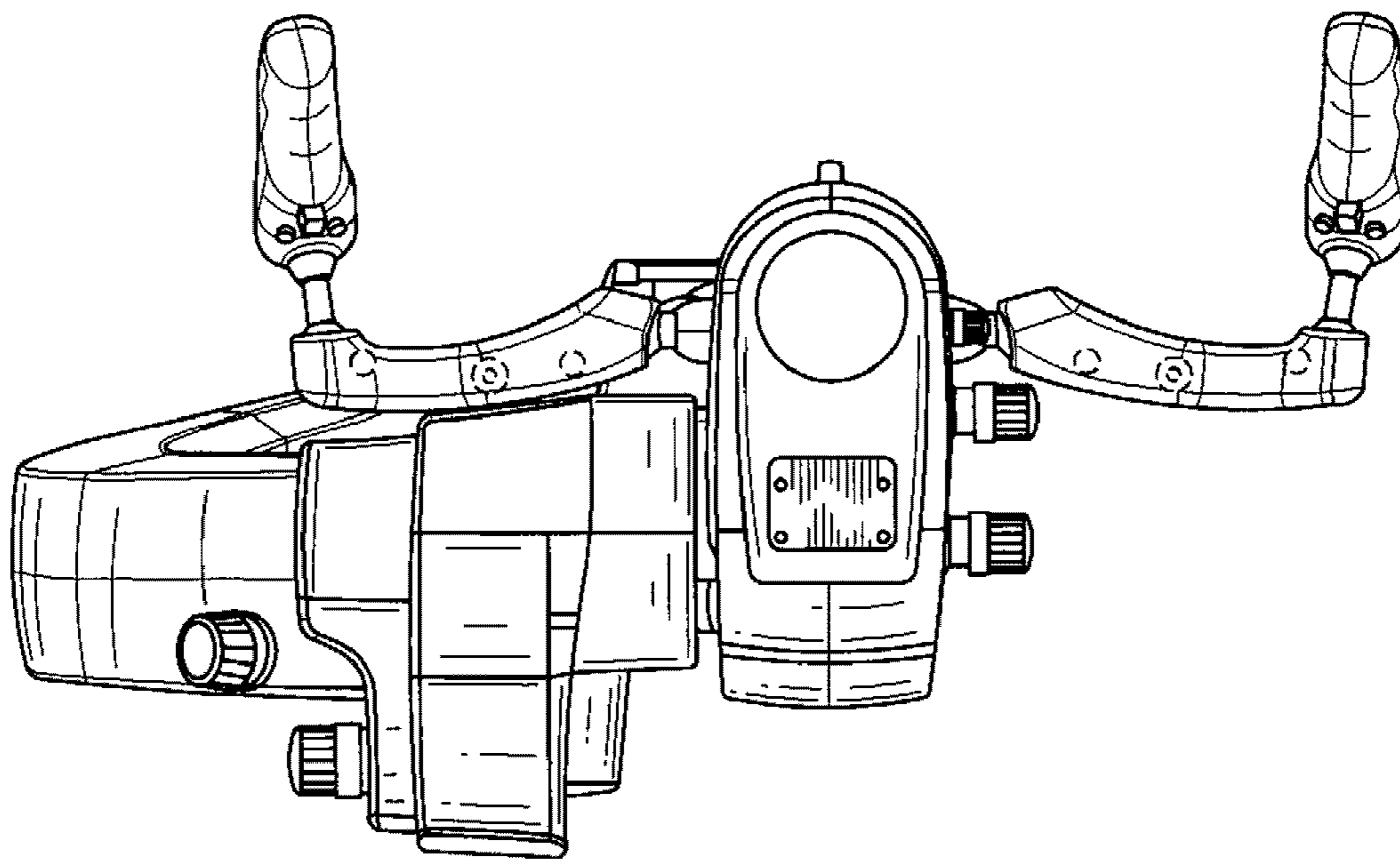


FIG. 4

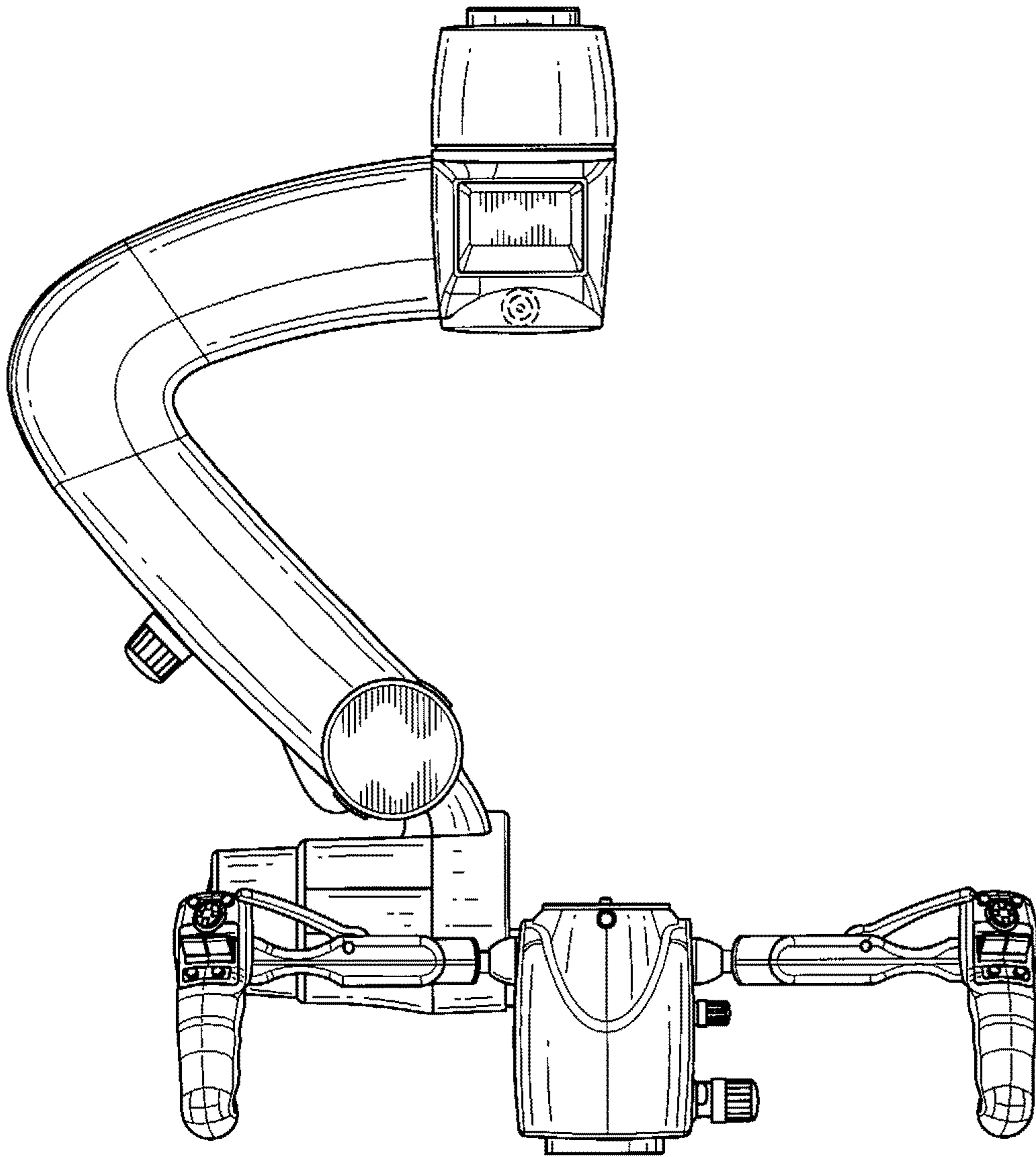


FIG. 5

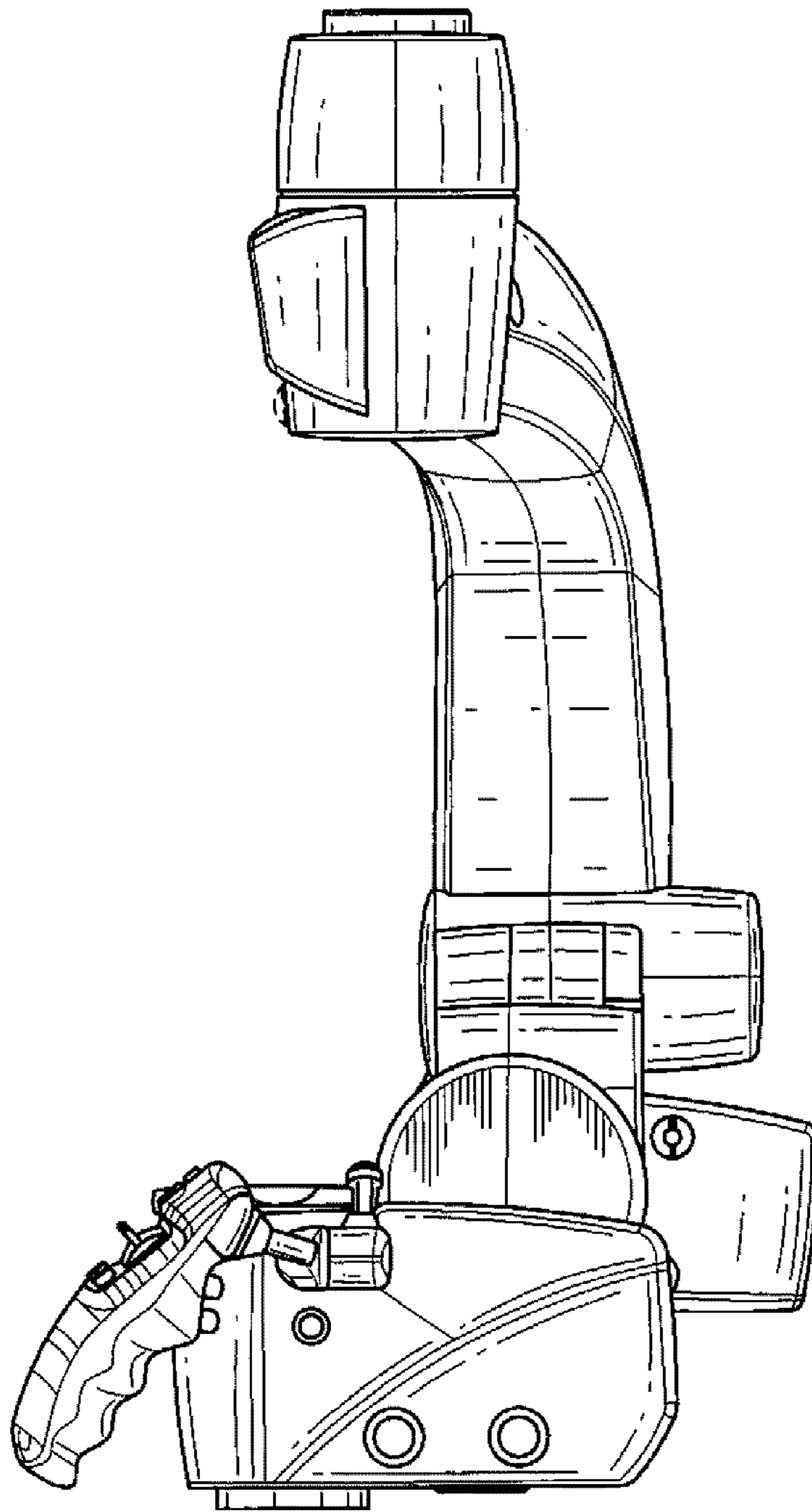


FIG. 6

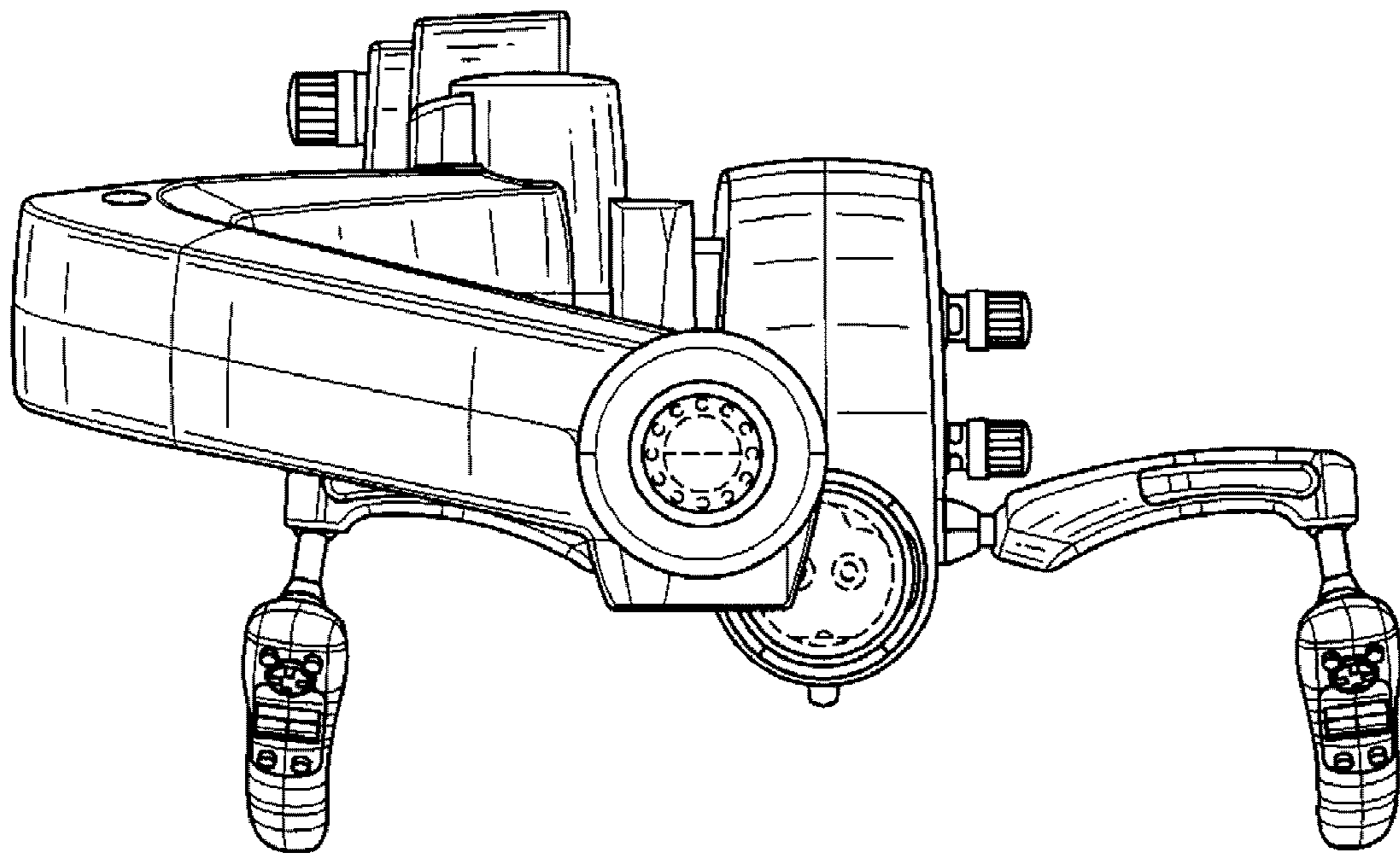


FIG. 7

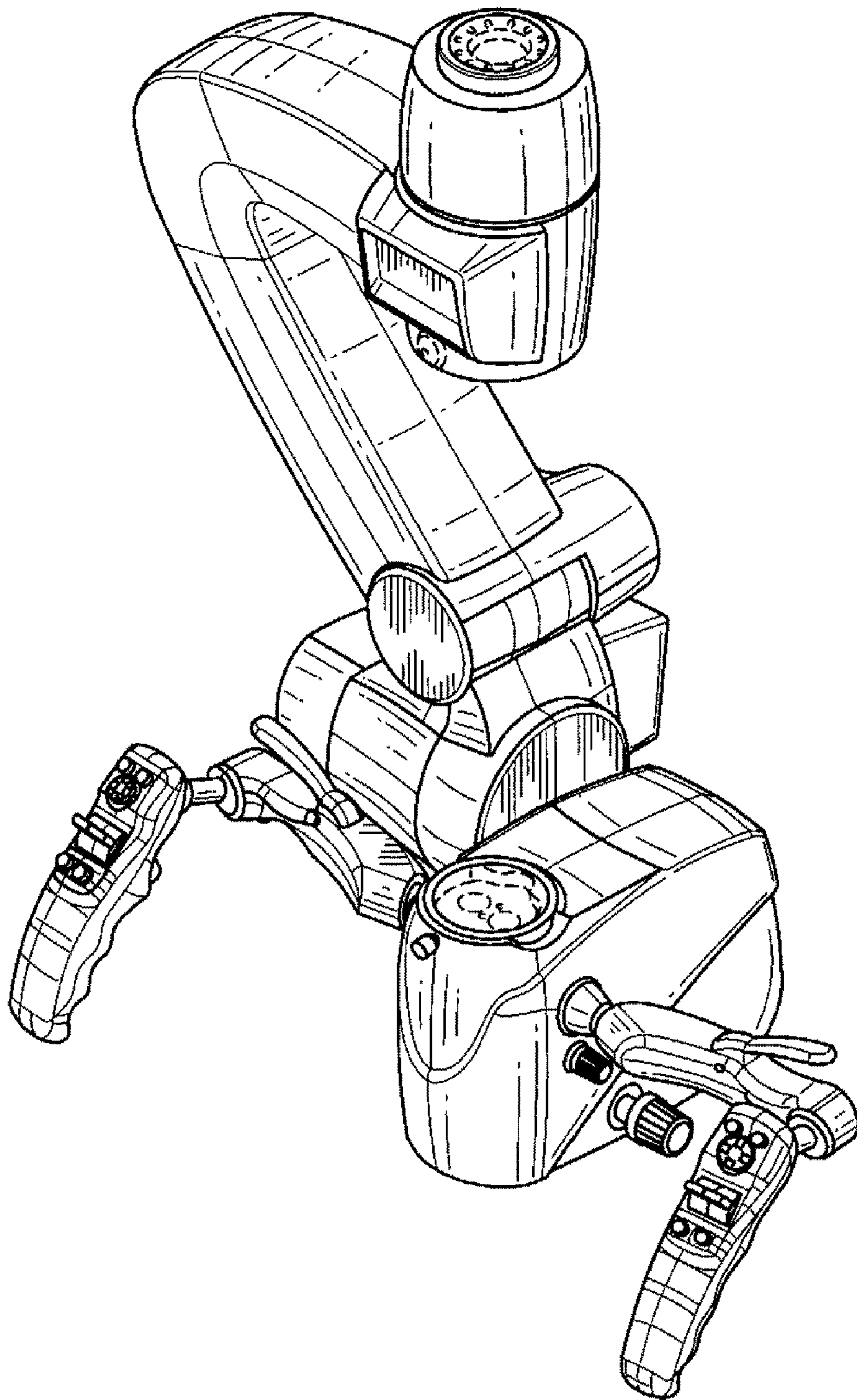


FIG. 8

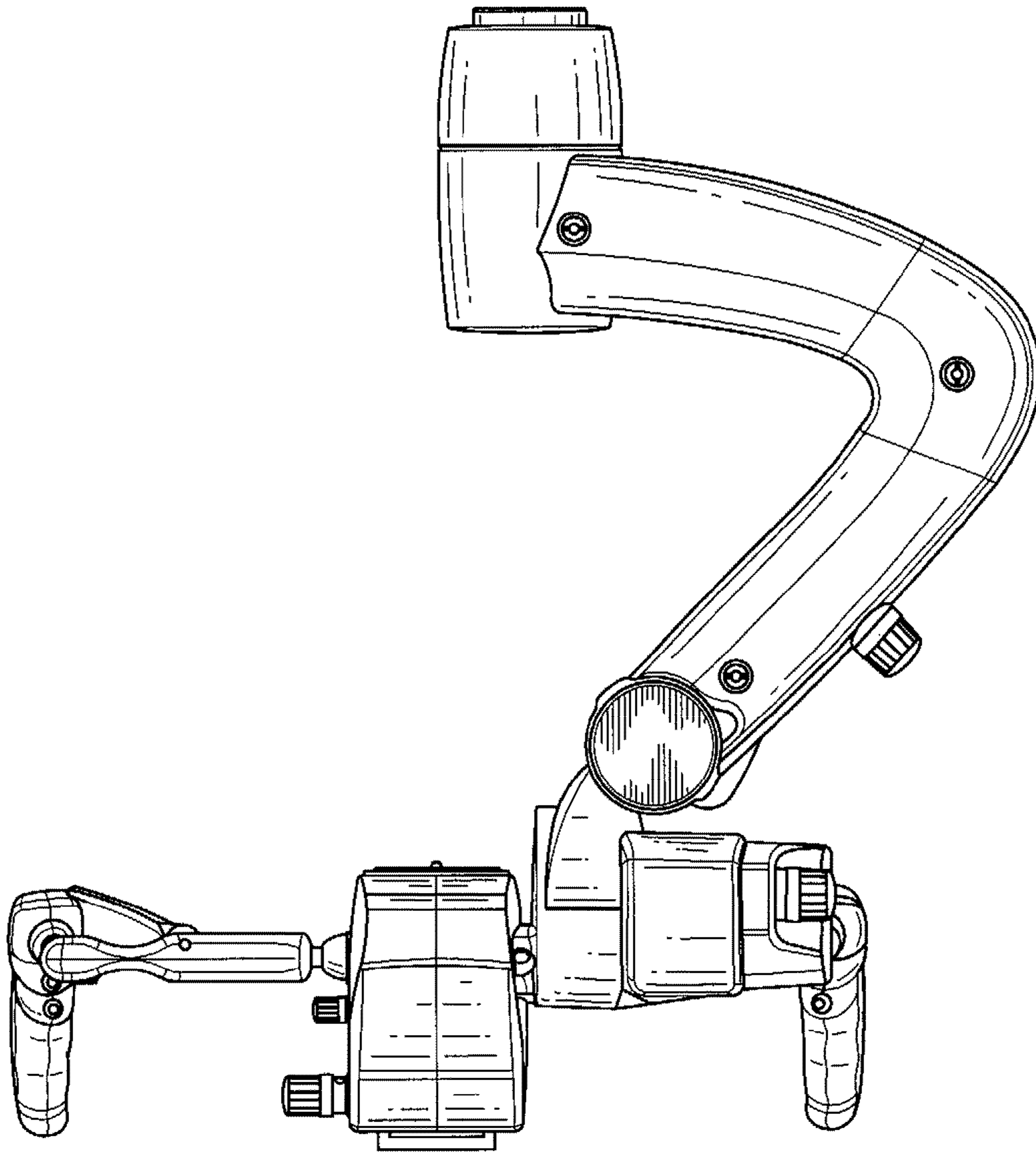


FIG. 9

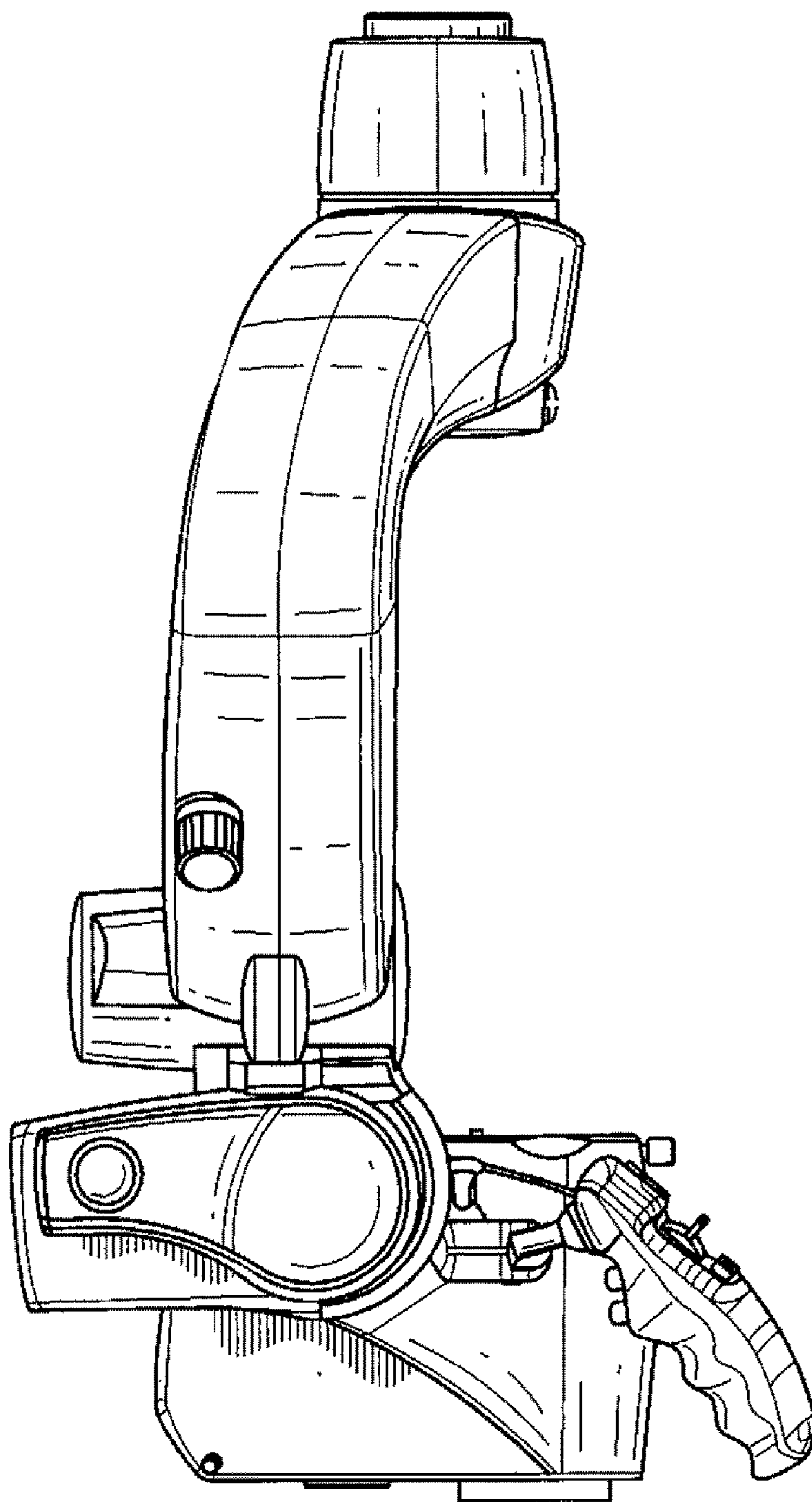


FIG. 10

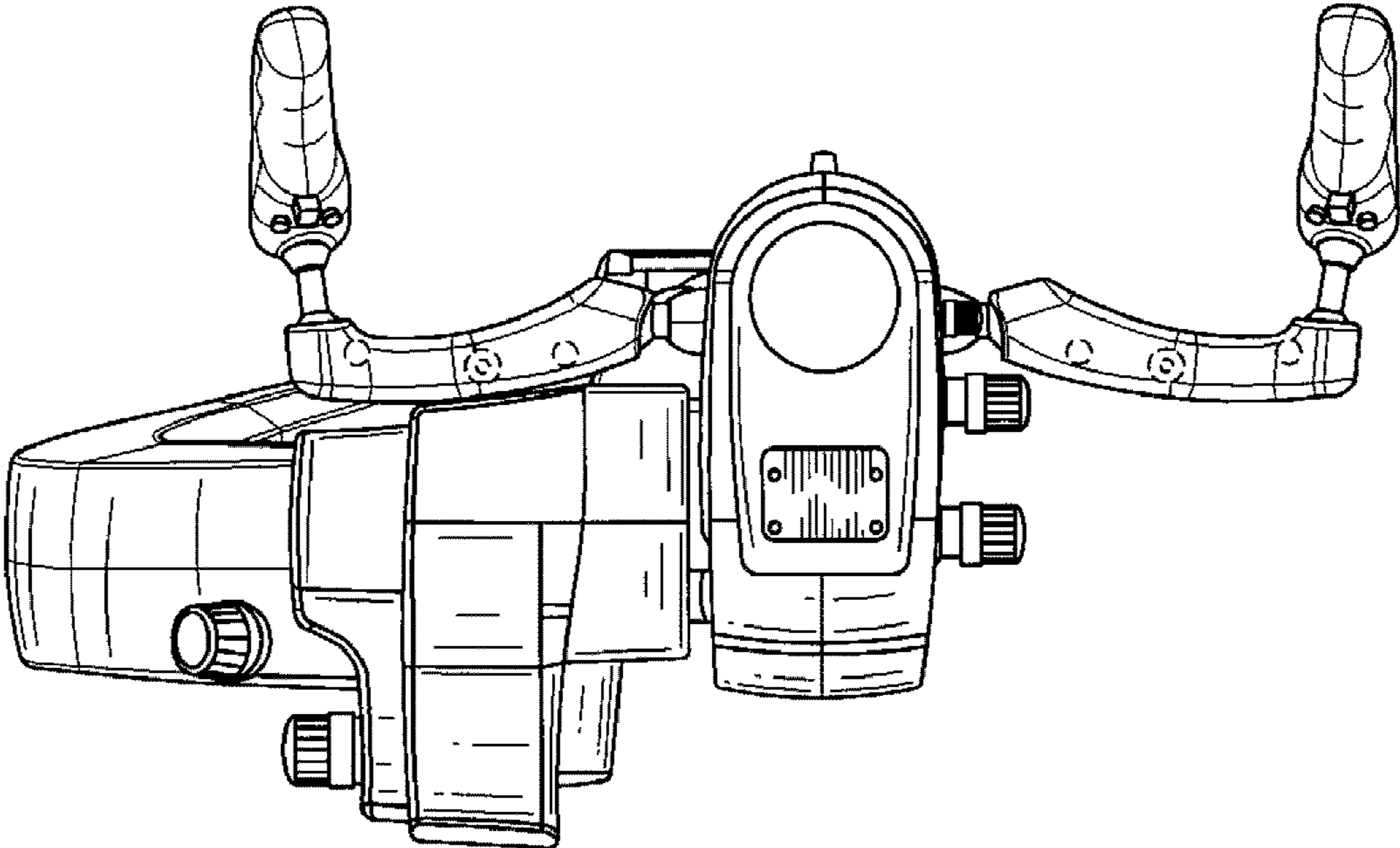


FIG. 11

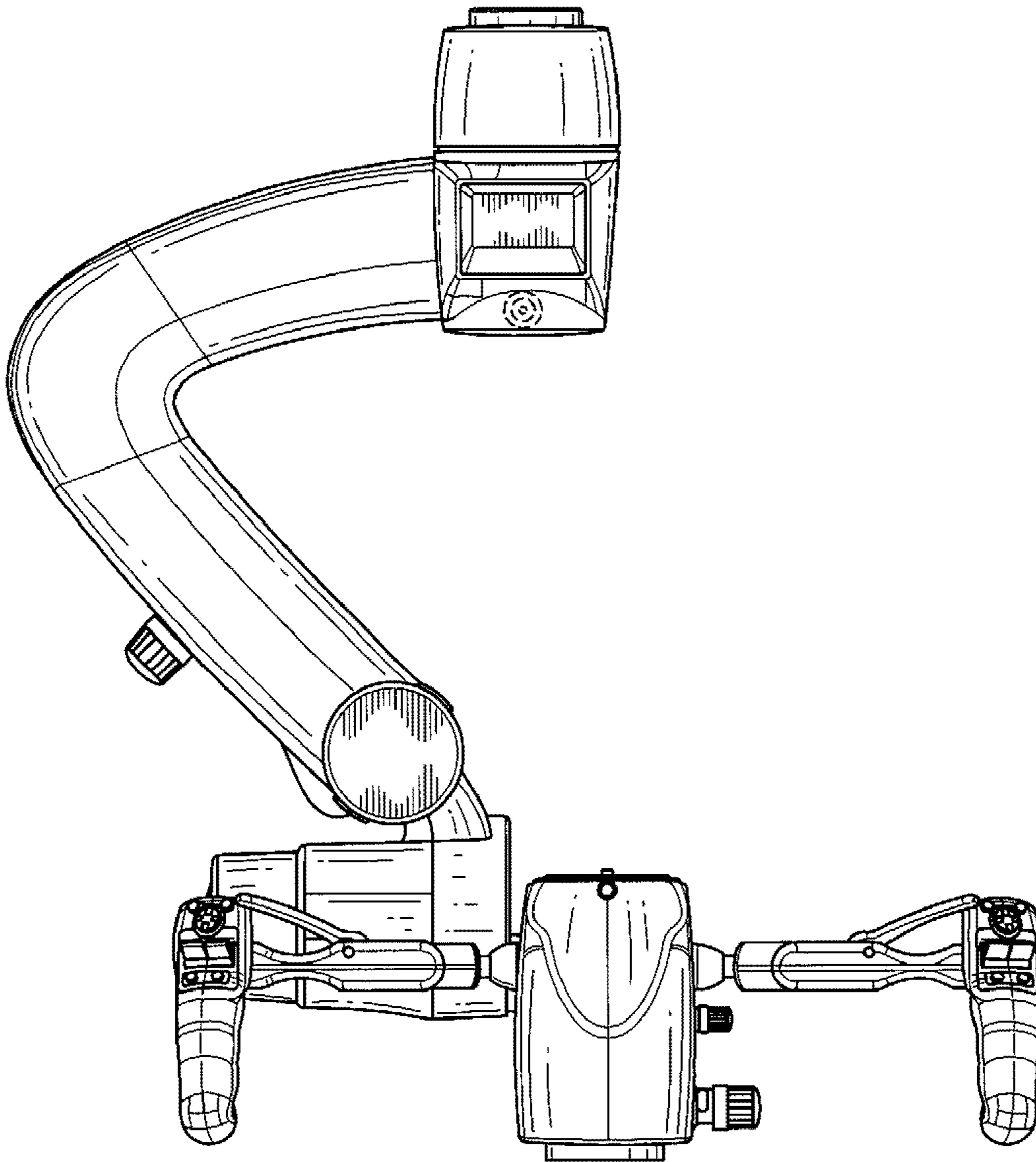


FIG. 12

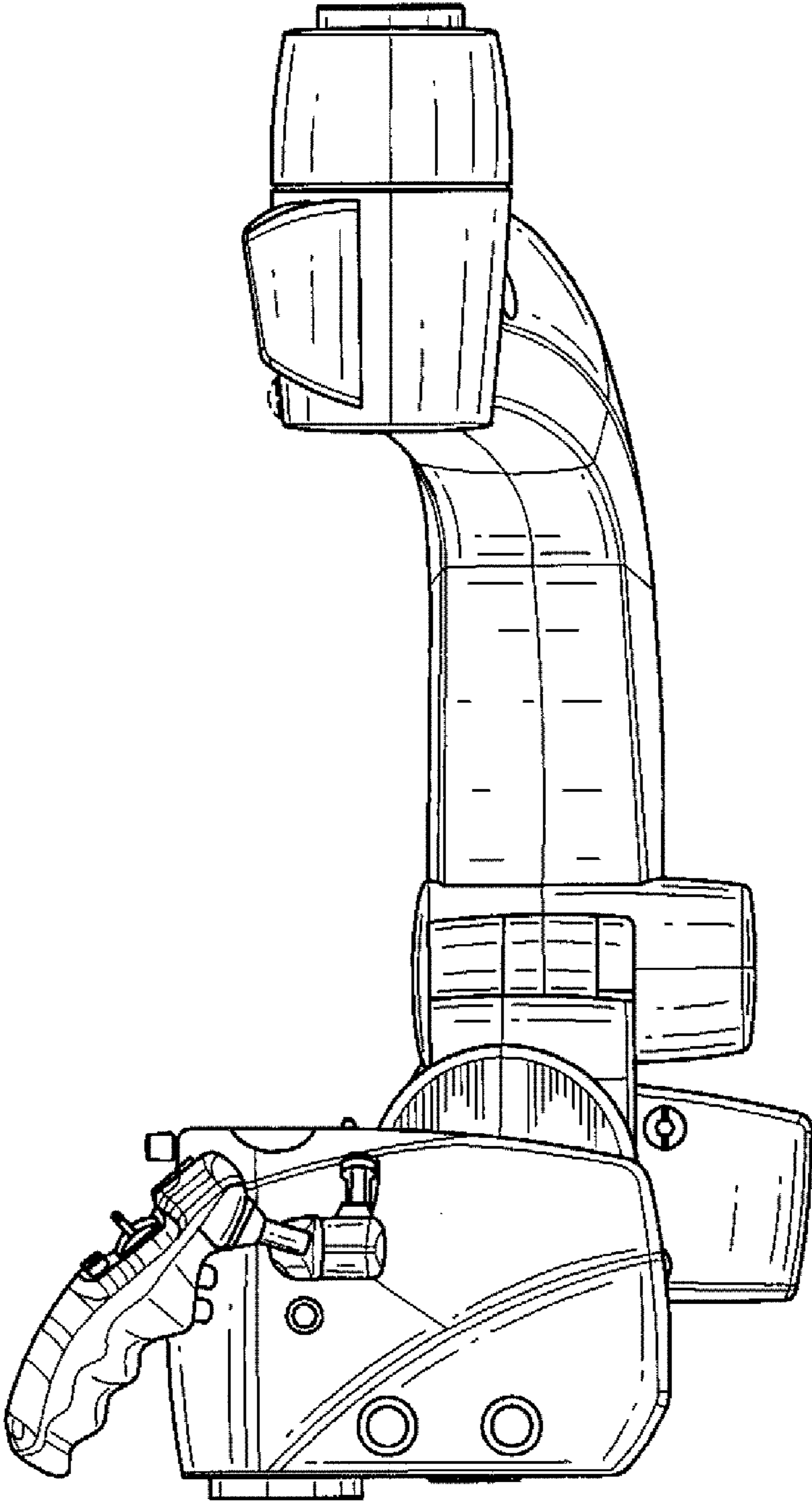


FIG. 13

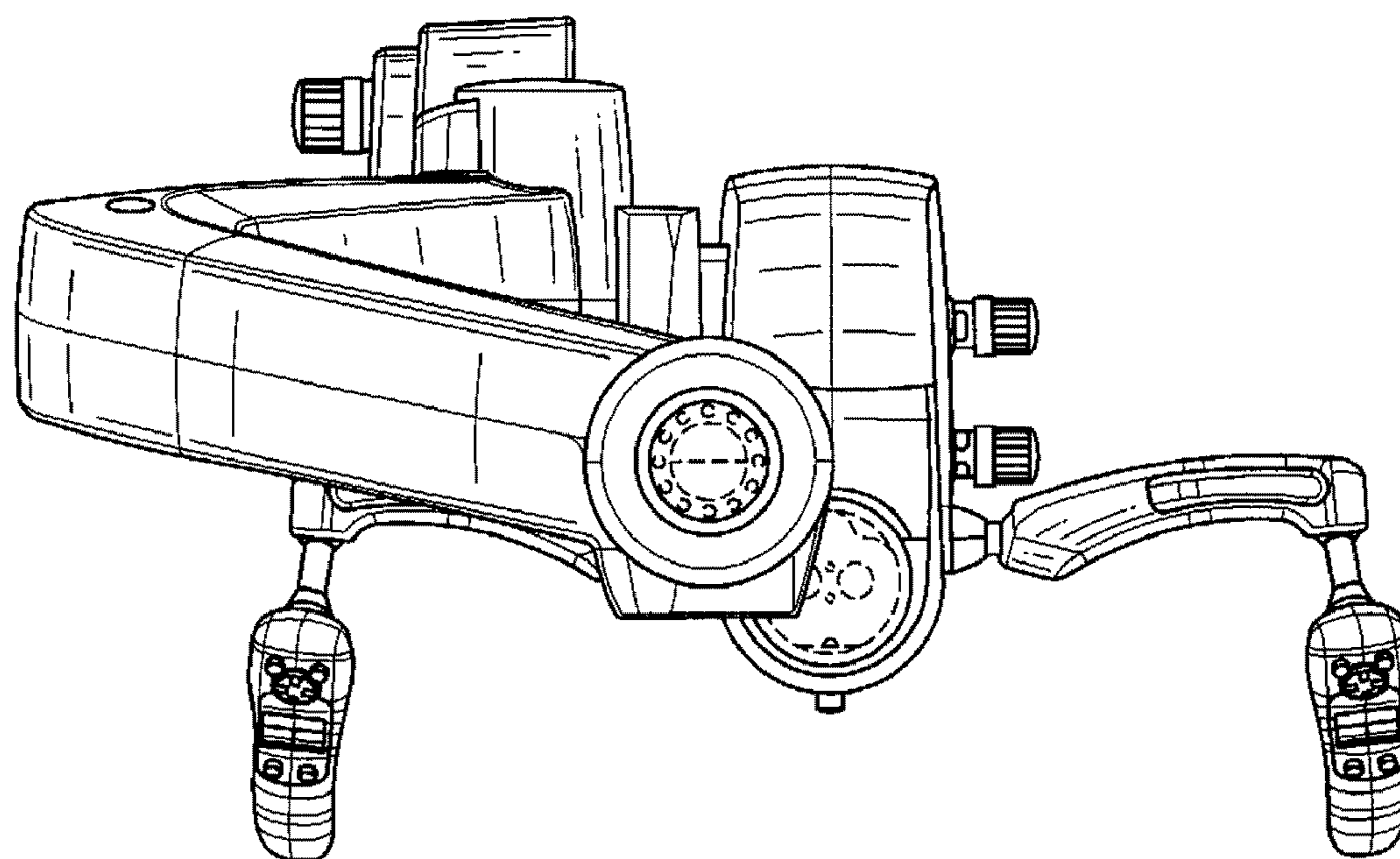


FIG. 14